Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/661,697	NAGAI ET AL.		
Examiner	Art Unit		
Nhon T. Dien	2621	,	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
Interfer	cence S	carch H	Btory	
mint-	out	12/08/06	N.D	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
LEE, YOUNG	12/01/06	M.D.		
LEE, PICHARD	m/01/06	N.D.		
VO, TUNG	201/06			
INVENTORS SEARCH	108/06	N.P		
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